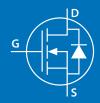
eGaN® FET DATASHEET EPC2055

EPC2055 – Enhancement Mode Power Transistor

 V_{DS} , 40 V $R_{DS(on)}\,,\,\,3.6~m\Omega$ $I_{D}\,,\,\,29~A$









Revised July 28, 2022

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low $R_{\rm DS(on)}$, while its lateral device structure and majority carrier diode provide exceptionally low $Q_{\rm G}$ and zero $Q_{\rm RR}$. The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Questions:	ACV
Ask a GaN	ASK AN EXPERT Ga
Expert	- Gu

	Maximum Ratings			
	PARAMETER	VALUE	UNIT	
W	Drain-to-Source Voltage (Continuous)	40		
V _{DS}	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150 °C)	48	V	
	Continuous (T _A = 25°C) 29		^	
I _D	Pulsed (25°C, T _{PULSE} = 300 μs)	161	A	
\/	Gate-to-Source Voltage 6		W	
VGS	Gate-to-Source Voltage	-4	V	
٦ _J	Operating Temperature	-40 to 150	50 °C	
T _{STG}	Storage Temperature	-40 to 150		

	Thermal Characteristics				
	PARAMETER	TYP	UNIT		
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1			
R _{OJB} Thermal Resistance, Junction-to-Board 2.5 °C/V					
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	64			

Note 1: $R_{\theta JA}$ is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf for details.

	Static Characteristics (T _J = 25°C unless otherwise stated)					
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
BV _{DSS}	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V, I}_{D} = 0.5 \text{ mA}$	40			V
I _{DSS}	Drain-Source Leakage	$V_{GS} = 0 \text{ V}, V_{DS} = 32 \text{ V}$		0.01	0.4	
	Gate-to-Source Forward Leakage	$V_{GS} = 5 V$		0.01	1.6	^
I _{GSS}	Gate-to-Source Forward Leakage#	$V_{GS} = 5 \text{ V}, T_J = 125^{\circ}\text{C}$		0.1	5	mA
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 V$		0.01	0.4	
V _{GS(TH)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 7 \text{ mA}$	0.7	1.1	2.5	V
R _{DS(on)}	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}, I_D = 15 \text{ A}$		3	3.6	mΩ
V_{SD}	Source-Drain Forward Voltage#	$I_S = 0.5 \text{ A}, V_{GS} = 0 \text{ V}$		1.9		V

[#] Defined by design. Not subject to production test.



Die Size: 2.5 x 1.5 mm

EPC2055 eGaN® FETs are supplied only in passivated die form with solder bars.

Applications

- DC-DC converters
- Isolated DC-DC converters
- Sync rectification
- High frequency (2 MHz) ultra-thin point of load converters with input 12 V – 24 V
- Lidar
- · USB-C battery chargers
- · LED lighting
- 12 V 24 V input motor drivers

Benefits

- · Ultra high efficiency
- No reverse recovery
- Ultra low Q_G
- Small footprint

Scan QR code or click link below for more information including reliability reports, device models, demo boards!



https://l.ead.me/EPC2055

EPC2055 eGaN® FET DATASHEET

	Dynamic Characteristics# (T _J = 25°C unless otherwise stated)					
	PARAMETER	TEST CONDITIONS	MIN	ТҮР	MAX	UNIT
C _{ISS}	Input Capacitance			841	1111	
C_{RSS}	Reverse Transfer Capacitance	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}$		8.8		
C_{OSS}	Output Capacitance			408	612	pF
C _{OSS(ER)}	Effective Output Capacitance, Energy Related (Note 2)	V _{DS} = 0 to 20 V, V _{GS} = 0 V 574 668				
C _{OSS(TR)}	Effective Output Capacitance, Time Related (Note 3)					
R_G	Gate Resistance			0.4		Ω
Q_{G}	Total Gate Charge	$V_{DS} = 20 \text{ V}, V_{GS} = 5 \text{ V}, I_D = 15 \text{ A}$		6.6	8.5	
Q _{GS}	Gate-to-Source Charge			2.3		
Q _{GD} Gate-to-Drain Charge V		$V_{DS} = 20 \text{ V}, I_D = 15 \text{ A}$		0.7		
Q _{G(TH)}	Gate Charge at Threshold	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}$ 13			nC	
Qoss	Output Charge			20		
Q _{RR}	Source-Drain Recovery Charge			0		

[#] Defined by design. Not subject to production test.

Note 2: $C_{OSS(ER)}$ is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS} . Note 3: $C_{OSS(TR)}$ is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS} .

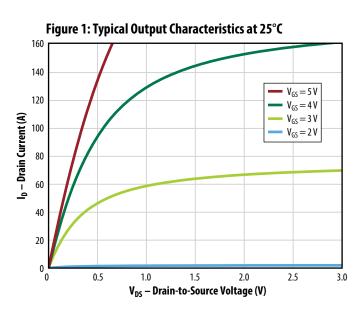
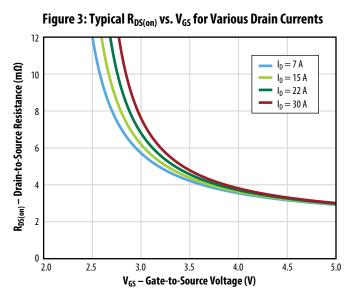
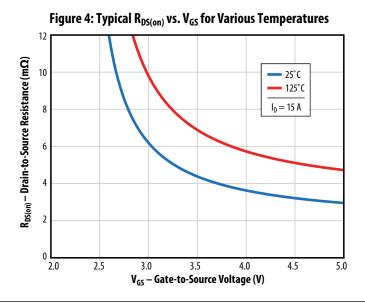


Figure 2: Typical Transfer Characteristics 140 **2**5°C 125°C 120 $V_{DS} = 3 V$ I_D – Drain Current (A) 60 40 20 0.5 1.0 1.5 4.5 V_{GS} – Gate-to-Source Voltage (V)





All measurements were done with substrate connected to source.

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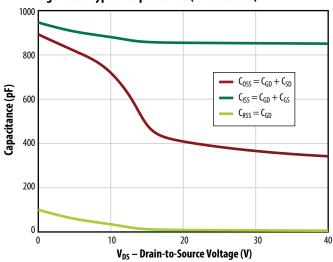


Figure 5b: Typical Capacitance (Log Scale)

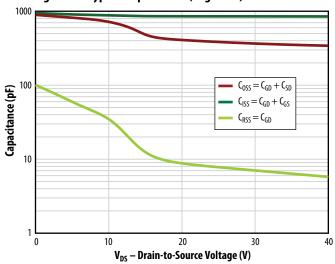


Figure 6: Typical Output Charge and Coss Stored Energy

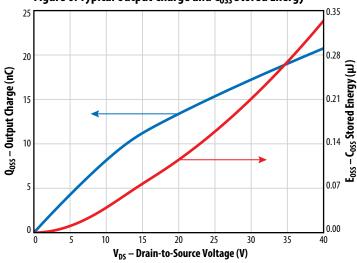


Figure 7: Typical Gate Charge

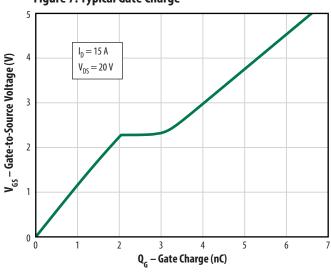


Figure 8: Typical Reverse Drain-Source Characteristics

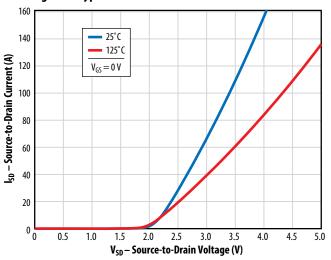
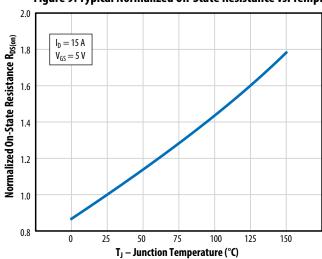
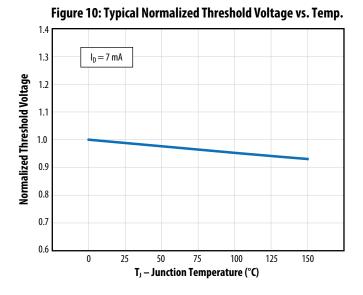


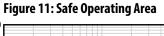
Figure 9: Typical Normalized On-State Resistance vs. Temp.

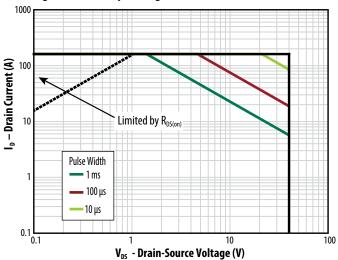


Note: Negative gate drive voltage increases the reverse drain-source voltage. EPC recommends 0 V for OFF.

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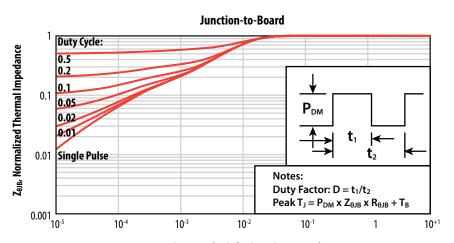




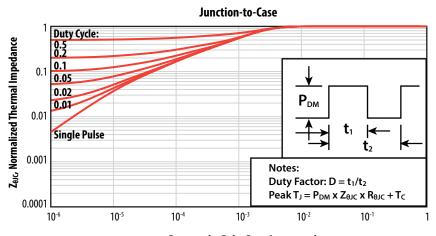


 $T_J = Max Rated$, $T_C = +25$ °C, Single Pulse

Figure 12: Typical Transient Thermal Response Curves



t₁, Rectangular Pulse Duration, seconds

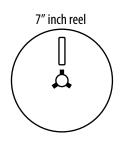


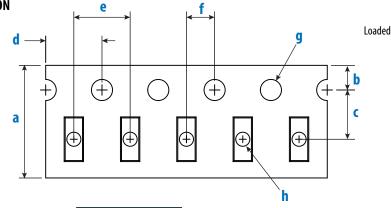
t₁, Rectangular Pulse Duration, seconds

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4 mm pitch, 8 mm wide tape on 7" reel





0.55

0.45

d Tape Feed Direction	\Rightarrow
ZZZZ AAAA SSOZ	Die orientation dot Gate solder bar is under this corner
Die is placed into p	oocket

solder bar side down (face side down)

	Dimension (mm)		
EPC2055 (Note 1)	Target	MIN	MAX
a	8.00	7.90	8.30
b	1.75	1.65	1.85
c (Note 2)	3.50	3.45	3.55
d	4.00	3.90	4.10
е	4.00	3.90	4.10
f (Note 2)	2.00	1.95	2.05
g	1.50	1.50	1.60

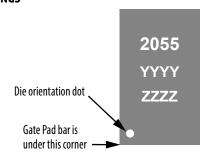
0.50

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/ JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

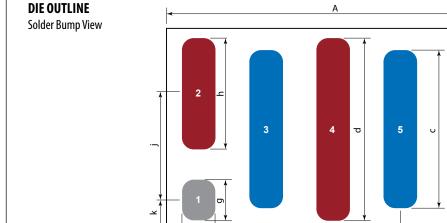
DIE MARKINGS

Side View



Dout		Laser Markings	
Part Number	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3
EPC2055	2055	YYYY	ZZZZ

6



√ f		< e →	
Seating plane			120 ± 12

	Micrometers		
DIM	MIN	Nominal	MAX
Α	2470	2500	2530
В	1470	1500	1530
c		1175	
d		1350	
e		500	
f		250	
g		300	
h		825	
j		787.5	
k		225	

Pad 1 is Gate;

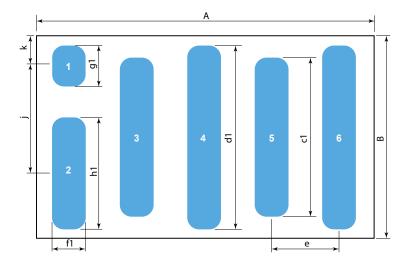
Pads 2,4,6 are Source;

Pads 3, 5 are Drain

eGaN® FET DATASHEET **EPC2055**

RECOMMENDED **LAND PATTERN**

(units in μ m)



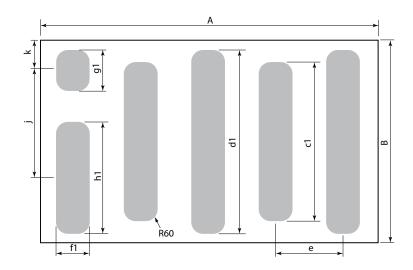
Land pattern is solder mask defined

DIM	Nominal
Α	2500
В	1500
c1	1155
d1	1330
e	500
f1	230
g1	280
h1	805
j	787.5
k	225

Pad 1 is Gate; Pads 2,4,6 are Source; Pads 3, 5 are Drain

RECOMMENDED STENCIL DRAWING

(units in µm)



DIM	Nominal
A	2500
В	1500
c1	1155
d1	1330
e	500
f1	230
g1	280
h1	805
j	787.5
k	225

Recommended stencil should be 4 mil (100 µm) thick, must be laser cut, openings per drawing.

The corner has a radius of R60.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Split stencil design can be provided upon request, but EPC has tested this stencil design and not found any scooping issues.

Additional assembly resources available at https://epc-co.com/epc/design-support

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EPC Patent Listing: https://epc-co.com/epc/about-epc/patents

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